





SN74AXC4T245 SCES877B - DECEMBER 2018 - REVISED APRIL 2024

SN74AXC4T245 Four-Bit Bus Transceiver with Configurable Voltage Translation and Tri-State Outputs

1 Features

Texas

INSTRUMENTS

- Fully configurable dual-rail design allows each port to operate with a power supply range from 0.65V to 3.6V
- Operating temperature from -40°C to +125°C
- Multiple direction control pins to allow simultaneous up and down translation
- Glitch-free power supply sequencing
- Up to 380Mbps support when translating from 1.8V ٠ to 3.3V
- V_{CC} isolation feature:
 - If either V_{CC} input is below 100mV, all I/Os outputs are disabled and become highimpedance
- Ioff supports Partial-Power-Down mode operation
- Compatible with AVC family level shifters
- Latch-up performance exceeds 100mA per JESD 78. Class II
- ESD protection exceeds JESD 22:
 - 8000V Human-Body Model
 - 1000V Charged-Device Model

2 Applications

- Enterprise and communications
- Industrial
- Personal electronics
- Wireless infrastructure
- **Building automation**
- Point of sale

3 Description

The SN74AXC4T245 is a four-bit noninverting bus transceiver that uses two individually configurable power-supply rails. The device is operational with both V_{CCA} and V_{CCB} supplies as low as 0.65V. The A port is designed to track V_{CCA}, which accepts any supply voltage from 0.65V to 3.6V. The B port is designed to track V_{CCB}, which also accepts any supply voltage from 0.65V to 3.6V. Additionally the SN74AXC4T245 is compatible with a single-supply system.

The SN74AXC4T245 device is designed for asynchronous communication between data buses. The device transmits data from the A bus to the B bus or from the B bus to the A bus, depending on the logic level of the direction-control inputs (1DIR and 2DIR). The output-enable inputs (1 \overline{OE} and 2 \overline{OE}) are used to disable the outputs so the buses are effectively isolated. The SN74AXC4T245 device is designed so the control pins (xDIR and x \overline{OE}) are referenced to V_{CCA}.

To put the level shifter I/Os in the high-impedance state during power up or power down, tie the $x\overline{OE}$ pins to V_{CCA} through a pullup resistor.

This device is fully specified for partial-power-down applications using the Ioff current. The Ioff protection circuitry ensures that no excessive current is drawn from or to an input, output, or combined I/O that is biased to a specific voltage while the device is powered down.

The design of the V_{CC} isolation feature allows both I/O ports to enter a high-impedance state by disabling their outputs if either V_{CCA} or V_{CCB} is less than 100mV.

Glitch-Free power supply sequencing allows either supply rail to be powered on or off in any order while providing robust power sequencing performance.

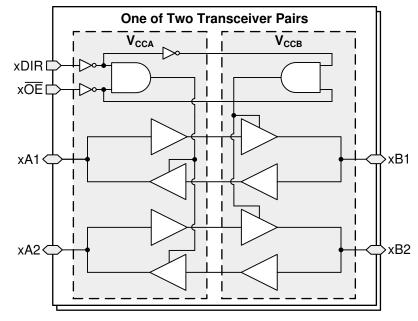
Package Information										
PART NUMBER	PACKAGE ⁽¹⁾	PACKAGE SIZE ⁽²⁾								
	PW (TSSOP, 16)	5mm × 6.4mm								
SN74AXC4T245	BQB (WQFN, 16)	3.5mm × 2.5mm								
	RSV (UQFN, 16)	2.6mm × 1.8mm								

For more information, see Section 11 (1)

The package size (length × width) is a nominal value and (2)includes pins, where applicable.







Functional Block Diagram



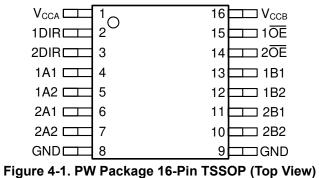
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4 Pin Configuration and Functions



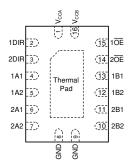


Figure 4-2. BQB Package 16-Pin WQFN (Transparent Top View)

	2 <u>0</u> E	1B1	1B2	2B1	
	16	15	14	13	
10E	1)	i		12	2B2
V_{CCB}	2			[]]]	GND
V_{CCA}	3			10	GND
1DIR	4			9	2A2
	5	6	7	8	
	2DIR	1A1	1A2	2A1	



PIN		NO.		TYPE ⁽¹⁾	DESCRIPTION					
NAME	PW	RSV	BQB		DESCRIPTION					
1A1	4	6	4	I/O	Input/output 1A1. Referenced to V _{CCA} .					
1A2	5	7	5	I/O	Input/output 1A2. Referenced to V _{CCA} .					
1B1	13	15	13	I/O	put/output 1B1. Referenced to V _{CCB} .					
1B2	12	14	12	I/O	Input/output 1B2. Referenced to V _{CCB} .					
1DIR	2	4	2	I	Direction-control input for '1' ports.					
1 <u>OE</u>	15	1	15	I	i-state output-mode enable. Pull \overline{OE} high to place '1' outputs in tri-state mode. eferenced to $V_{CCA}.$					
2A1	6	8	6	I/O	Input/output 2A1. Referenced to V _{CCA} .					
2A2	7	9	7	I/O	Input/output 2A2. Referenced to V _{CCA} .					
2B1	11	13	11	I/O	Input/output 2B1. Referenced to V _{CCB} .					
2B2	10	12	10	I/O	Input/output 2B2. Referenced to V _{CCB} .					
2DIR	3	5	3	I	Direction-control input for '2' ports.					
2 <u>OE</u>	14	16	14	I	Tri-state output-mode enable. Pull $\overline{\text{OE}}$ high to place '2' outputs in tri-state mode. Referenced to V_{CCA} .					
GND	8, 9	10, 11	8, 9	_	Ground.					
V _{CCA}	1	3	1	_	A-port power supply voltage. $0.65V \le V_{CCA} \le 3.6V$.					
V _{CCB}	16	2	16	_	B-port power supply voltage. $0.65V \le V_{CCB} \le 3.6V$.					

Table 4-1. Pin Functions

(1) I = input, O = output



5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾

			MIN	MAX	UNIT	
V _{CCA}	Supply voltage A		-0.5	4.2	V	
V _{CCB}	Supply voltage B		-0.5	4.2	V	
		I/O Ports (A Port)	-0.5	4.2		
VI	Input Voltage ⁽²⁾	I/O Ports (B Port)	-0.5	4.2	V	
		Control Inputs	-0.5	4.2		
v	Voltage explicit to any extruction the high impedance or neuror off state (2)	A Port	-0.5	4.2	V	
Vo	Voltage applied to any output in the high-impedance or power-off state ⁽²⁾	B Port	-0.5	4.2	v	
V	Voltage applied to any output in the high or low state ^{(2) (3)}	A Port	-0.5	V _{CCA} + 0.2	V	
Vo	Voltage applied to any output in the high of low state (-) (-)	B Port	-0.5	V _{CCB} + 0.2	v	
I _{IK}	Input clamp current	V _I < 0	-50		mA	
I _{OK}	Output clamp current	V _O < 0	-50		mA	
I _O	Continuous output current		-50	50	mA	
	Continuous current through V _{CC} or GND		-100	100	mA	
Tj	Junction Temperature			150	°C	
T _{stg}	Storage temperature		-65	150	°C	

(1) Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) The input voltage and output negative-voltage ratings may be exceeded if the input and output current ratings are observed.

(3) The output positive-voltage rating may be exceeded up to 4.2V maximum if the output current rating is observed.

5.2 ESD Ratings

			VALUE	UNIT
V	Electrostatic discharge	Human body model (HBM), per ANSI/ESDA/JEDEC JS-001 ⁽¹⁾		V
V _(ESD)	Electrostatic discharge	Charged device model (CDM), per JEDEC specification JESD22-C101 ⁽²⁾	±1000	v

(1) JEDEC document JEP155 states that 500V HBM allows safe manufacturing with a standard ESD control process.

(2) JEDEC document JEP157 states that 250V CDM allows safe manufacturing with a standard ESD control process.



5.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)(1) 2

				MIN	MAX	UNIT		
V _{CCA}	Supply voltage A			0.65	3.6	V		
V _{CCB}	Supply voltage B			0.65	3.6	V		
			V _{CCI} = 0.65V - 0.75V	V _{CCI} x 0.70				
			V _{CCI} = 0.76V - 1V	V _{CCI} x 0.70				
		Data Inputs	V _{CCI} = 1.1V - 1.95V	V _{CCI} x 0.65				
V _{IH}			V _{CCI} = 2.3V - 2.7V	1.6				
	Lligh lovel input veltage		V _{CCI} = 3V - 3.6V	2		v		
	High-level input voltage		V _{CCA} = 0.65V - 0.75V	V _{CCA} x 0.70		v		
			V _{CCA} = 0.76V - 1V	V _{CCA} x 0.70				
		Control Inputs(xDIR, x \overline{OE}) Referenced to V _{CCA}	V _{CCA} = 1.1V - 1.95V	V _{CCA} x 0.65				
			V _{CCA} = 2.3V - 2.7V	1.6				
			V _{CCA} = 3V - 3.6V	2				
			V _{CCI} = 0.65V - 0.75V					
			V _{CCI} = 0.76V - 1V		V _{CCI} x 0.30			
		Data Inputs	V _{CCI} = 1.1V - 1.95V		V _{CCI} x 0.35			
			V _{CCI} = 2.3V - 2.7V		0.7			
√ _{IL}	Low-level input voltage		V _{CCI} = 3V - 3.6V		0.8	v		
∕ IL	Low-level input voltage		V _{CCA} = 0.65V - 0.75V		V _{CCA} x 0.30	v		
			V _{CCA} = 0.76V - 1V		V _{CCA} x 0.30			
		Control Inputs(xDIR, x \overline{OE}) Referenced to V _{CCA}	V _{CCA} = 1.1V - 1.95V		V _{CCA} x 0.35			
			V _{CCA} = 2.3V - 2.7V		0.7			
			V _{CCA} = 3V - 3.6V		0.8			
V _I	Input voltage ¹			0	3.6	V		
,	Output voltage	Active State		0	V _{CCO}	V		
/o	Output voltage	Tri-State	Tri-State					
∆t/∆v ²	Input transition rate				10	ns/V		
Γ _A	Operating free-air tempe	rature		-40	125	°C		

(1)

 V_{CCI} is the V_{CC} associated with the input port. V_{CCO} is the V_{CC} associated with the output port. All unused inputs of the device must be held at VCC or GND for proper device operation. Refer to the TI application report, (2) Implications of Slow or Floating CMOS Inputs.

5.4 Thermal Information

		SN74AXC4T245							
	THERMAL METRIC ⁽¹⁾	PW (TSSOP)	RSV (UQFN)	BQB (WQFN)	UNIT				
		16 PINS	16 PINS	16 PINS					
R _{0JA}	Junction-to-ambient thermal resistance	126.9	130.1	73.0	°C/W				
R _{0JC(top)}	Junction-to-case (top) thermal resistance	49.3	70.3	35.1	°C/W				
R _{θJB}	Junction-to-board thermal resistance	74.3	57.4	42.8	°C/W				
Ψ _{JT}	Junction-to-top characterization parameter	8.1	4.6	4.6	°C/W				
Ψјв	Junction-to-board characterization parameter	73.4	55.8	42.8	°C/W				
R _{0JC(bottom)}	Junction-to-case (bottom) thermal resistance	NA	NA	10.2	°C/W				

For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application (1) report.



5.5 Electrical Characteristics

						Operating free-air temperature (T _A)						
P	ARAMETER	TEST	CONDITIONS	V _{CCA}	V _{CCB}	-40)°C to 85°C	-40	°C to 125°C	;	UNI	
						MIN	TYP ⁽⁴⁾ MAX	MIN	TYP ⁽⁴⁾	MAX		
			Ι _{ΟΗ} = –100μΑ	0.7V - 3.6V	0.7V - 3.6V	V _{CCO} – 0.1		V _{CCO} – 0.1				
			Ι _{ΟΗ} = –50μΑ	0.65V	0.65V	0.55		0.55				
	High-level output voltage		I _{OH} = -200μA	0.76V	0.76V	0.58		0.58				
			I _{OH} = –500µА	0.85V	0.85V	0.65		0.65				
он		V _I = V _{IH}	I _{OH} = -3mA	1.1V	1.1V	0.85		0.85			V	
			I _{OH} = -6mA	1.4V	1.4V	1.05		1.05				
			I _{OH} = -8mA	1.65V	1.65V	1.2		1.2				
			I _{OH} = -9mA	2.3V	2.3V	1.75		1.75				
			I _{OH} = -12mA	3V	3V	2.3		2.3				
			I _{OL} = 100μA	0.7V - 3.6V	0.7V - 3.6V		0.1			0.1		
			I _{OL} = 50μA	0.65V	0.65V		0.1			0.1		
			I _{OL} = 200μA	0.76V	0.76V		0.18			0.18		
V _{OL}	Low-level output	V _I = V _{IL}	I _{OL} = 500μA	0.85V	0.85V		0.2			0.2		
			I _{OL} = 3mA	1.1V	1.1V		0.25			0.25	v	
	Volkago		I _{OL} = 6mA	1.4V	1.4V		0.35			0.35		
			I _{OL} = 8mA	1.65V	1.65V		0.45			0.45		
			I _{OL} = 9mA	2.3V	2.3V		0.55			0.55		
			I _{OL} = 12mA	3V	3V		0.7			0.7		
	Input leakage	Control inputs (xDIR, x \overline{OE}): V ₁ = V _{CCA} or GND		0.65V- 3.6V	0.65V- 3.6V	-0.5	0.5	-1		1	μA	
	current	Data Input V _I = V _{CCI} o	ts (xAx, xBx) or GND	0.65V- 3.6V	0.65V- 3.6V	-4	4	-8		8	μA	
off	Partial power	A or B Por		0V	0V - 3.6V	-4	4	-8		8	µ/	
off	down current	$V_1 \text{ or } V_0 =$	0V - 3.6V	0V - 3.6V	0V	-4	4	-8		8	μ	
oz	Tri-state output current ⁽³⁾	A or B Por V _I = V _{CCI} or or GND, C	or GND, V _O = V _{CCO}	3.6V	3.6V	-4	4	-8		8	μA	
				0.65V- 3.6V	0.65V- 3.6V		13			26		
CCA	V _{CCA} supply current	V _I = V _{CCI} or GND	I _O = 0	0V	3.6V	-2		-12			μ	
	Garrone			3.6V	0V		8			16		
				0.65V- 3.6V	0.65V- 3.6V		13			26		
ССВ	V _{CCB} supply current	V _I = V _{CCI} or GND	I _O = 0	0V	3.6V		8			16	μA	
				3.6V	0V	-2		-12				
сса + ссв	Combined supply current	V _I = V _{CCI} or GND	I _O = 0	0.65V- 3.6V	0.65V- 3.6V		20			40	μ	
2 _i	Control input capacitance	V _I = 3.3V	or GND	3.3V	3.3V		4.5		4.5		pŀ	
C _{io}	Data I/O capacitance	OE = V _{CC} +1MHz -1	_A , V _O = 1.65V DC 6dBm sine wave	3.3V	3.3V		6.6		6.6		pł	

over operating free-air temperature range (unless otherwise noted) (1) (2)

(1)

 V_{CCI} is the V_{CC} associated with the input port. V_{CCO} is the V_{CC} associated with the output port. (2)

For I/O ports, the parameter I_{OZ} includes the input leakage current. All typical data is taken at 25°C.

(3) (4)

5.6 Switching Characteristics, V_{CCA} = 0.7V

See Figure 1 and Table	1 for test circuit and loading.	See Figure 2, Figure 3, and	d Figure 4 for measurement waveforms.

		FROM TO										I	B-Port S	Supply	Voltage	(V _{CCB})							
P	PARAMETER		то	Test Conditions	0.7 ± 0	0.05V	0.8 ± 0	.04V	0.9 ± 0	.045V	1.2 ± (0.1V	1.5 ±	0.1V	1.8 ± ().15V	2.5 ± (0.2V	3.3 ±	0.3V	UNIT		
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX			
		A	в	–40°C to 85°C	0.5	155	0.5	108	0.5	76	0.5	40	0.5	37	0.5	40	0.5	67	0.5	185			
+	Propagation	A	D	–40°C to 125°C	0.5	155	0.5	108	0.5	76	0.5	40	0.5	37	0.5	40	0.5	67	0.5	185	ns		
t _{pd}	delay	В	A	–40°C to 85°C	0.5	156	0.5	128	0.5	106	0.5	55	0.5	21	0.5	15	0.5	11	0.5	10			
				D		–40°C to 125°C	0.5	156	0.5	128	0.5	106	0.5	55	0.5	21	0.5	15	0.5	11	0.5	10	
				ŌĒ	A	–40°C to 85°C	0.5	156	0.5	156	0.5	156	0.5	156	0.5	156	0.5	156	0.5	156	0.5	156	
+	Disable time			–40°C to 125°C	0.5	156	0.5	156	0.5	156	0.5	156	0.5	156	0.5	156	0.5	156	0.5	156	1 1		
t _{dis}		OE	в	–40°C to 85°C	0.5	154	0.5	121	0.5	101	0.5	55	0.5	54	0.5	56	0.5	65	0.5	125	ns		
				–40°C to 125°C	0.5	154	0.5	121	0.5	101	0.5	55	0.5	54	0.5	56	0.5	65	0.5	125			
		ŌĒ	A	–40°C to 85°C	0.5	238	0.5	238	0.5	238	0.5	238	0.5	238	0.5	238	0.5	238	0.5	238			
+	Enable time		A	–40°C to 125°C	0.5	238	0.5	238	0.5	238	0.5	238	0.5	238	0.5	238	0.5	238	0.5	238			
t _{en}		ŌE	В	–40°C to 85°C	0.5	286	0.5	194	0.5	146	0.5	94	0.5	76	0.5	70	0.5	69	0.5	146	ns		
				-40°C to 125°C	0.5	286	0.5	194	0.5	146	0.5	94	0.5	76	0.5	70	0.5	69	0.5	146			

5.7 Switching Characteristics, V_{CCA} = 0.8V

										I	B-Port S	Supply	Voltage	(V _{ссв})							
P	ARAMETER	FROM	то	Test Conditions	0.7 ± 0	.05V	0.8 ± 0	.04V	0.9 ± 0.	.045V	1.2 ± (0.1V	1.5 ± (0.1V	1.8 ± 0).15V	2.5 ±	0.2V	3.3 ±	0.3V	UNIT
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
		^	в	–40°C to 85°C	0.5	128	0.5	88	0.5	63	0.5	29	0.5	24	0.5	23	0.5	24	0.5	34	
+	Propagation	A		–40°C to 125°C	0.5	128	0.5	88	0.5	63	0.5	29	0.5	24	0.5	23	0.5	24	0.5	34	ns
Lpd	delay	R A	^	–40°C to 85°C	0.5	108	0.5	88	0.5	70	0.5	38	0.5	21	0.5	15	0.5	11	0.5	10	
		ВА		–40°C to 125°C	0.5	108	0.5	88	0.5	70	0.5	38	0.5	21	0.5	15	0.5	11	0.5	10	
			^	–40°C to 85°C	0.5	103	0.5	103	0.5	103	0.5	103	0.5	103	0.5	103	0.5	103	0.5	103	
t	OE Disable time		A	–40°C to 125°C	0.5	103	0.5	103	0.5	103	0.5	103	0.5	103	0.5	103	0.5	103	0.5	103	ns
t _{dis}	s Disable time	OF	B	–40°C to 85°C	0.5	143	0.5	110	0.5	90	0.5	42	0.5	36	0.5	36	0.5	37	0.5	47	113
	OE B		–40°C to 125°C	0.5	143	0.5	110	0.5	90	0.5	42	0.5	36	0.5	36	0.5	37	0.5	47		



5.7 Switching Characteristics, V_{CCA} = 0.8V (continued)

	<u> </u>					,	<u> </u>	,					Voltage								
F	ARAMETER	FROM	то	Test Conditions	0.7 ± 0	0.05V	0.8 ± 0	.04V	0.9 ± 0		1.2 ±		1.5 ±		1.8 ± 0).15V	2.5 ± (0.2V	3.3 ± (0.3V	UNIT
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
		OE	Δ	–40°C to 85°C	0.5	143	0.5	143	0.5	143	0.5	143	0.5	143	0.5	143	0.5	143	0.5	143	
+	Enable time			–40°C to 125°C	0.5	143	0.5	143	0.5	143	0.5	143	0.5	143	0.5	143	0.5	143	0.5	143	ns
t _{en}		OE	в	–40°C to 85°C	0.5	243	0.5	172	0.5	129	0.5	79	0.5	60	0.5	54	0.5	48	0.5	53	115
				–40°C to 125°C	0.5	243	0.5	172	0.5	129	0.5	79	0.5	60	0.5	54	0.5	48	0.5	53	

See Figure 1 and Table 1 for test circuit and loading. See Figure 2, Figure 3, and Figure 4 for measurement waveforms.

5.8 Switching Characteristics, V_{CCA} = 0.9V

										E	B-Port S	Supply	Voltage	(V _{CCB})							
P.	ARAMETER	FROM	то	Test Conditions	0.7 ± 0).05V	0.8 ± 0	.04V	0.9 ± 0.	045V	1.2 ± (0.1V	1.5 ±	0.1V	1.8 ± ().15V	2.5 ±	0.2V	3.3 ±	0.3V	UNIT
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
		A	в	–40°C to 85°C	0.5	106	0.5	70	0.5	53	0.5	24	0.5	18	0.5	17	0.5	16	0.5	19	
+	Propagation			–40°C to 125°C	0.5	106	0.5	70	0.5	53	0.5	24	0.5	18	0.5	17	0.5	16	0.5	19	20
t _{pd}	delay	P	^	–40°C to 85°C	0.5	76	0.5	63	0.5	53	0.5	27	0.5	18	0.5	13	0.5	10	0.5	9	ns
		В А 		–40°C to 125°C	0.5	76	0.5	63	0.5	53	0.5	27	0.5	18	0.5	13	0.5	10	0.5	9	
		OE /	^	–40°C to 85°C	0.5	81	0.5	81	0.5	81	0.5	81	0.5	81	0.5	81	0.5	81	0.5	81	
+	Disable time			–40°C to 125°C	0.5	81	0.5	81	0.5	81	0.5	81	0.5	81	0.5	81	0.5	81	0.5	81	20
t _{dis}		OE	В	–40°C to 85°C	0.5	138	0.5	105	0.5	84	0.5	37	0.5	30	0.5	28	0.5	26	0.5	30	ns
				–40°C to 125°C	0.5	138	0.5	105	0.5	84	0.5	37	0.5	30	0.5	28	0.5	26	0.5	30	
			A	–40°C to 85°C	0.5	95	0.5	95	0.5	95	0.5	95	0.5	95	0.5	95	0.5	95	0.5	95	
+	Enable time			–40°C to 125°C	0.5	95	0.5	95	0.5	95	0.5	95	0.5	95	0.5	95	0.5	95	0.5	95	nc
Len			в	–40°C to 85°C	0.5	222	0.5	148	0.5	116	0.5	71	0.5	52	0.5	46	0.5	39	0.5	39	ns
			–40°C to 125°C	0.5	222	0.5	148	0.5	116	0.5	71	0.5	52	0.5	46	0.5	39	0.5	39		



5.9 Switching Characteristics, V_{CCA} = 1.2V

See Figure 1 and Table 1 for test circuit and loading	See Figure 2, Figure 3, and Fi	oure 4 for measurement waveforms.
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										l	B-Port S	Supply	Voltage	(V _{CCB})							
P	ARAMETER	FROM	то	Test Conditions	0.7 ± 0	0.05V	0.8 ± 0	.04V	0.9 ± 0	.045V	1.2 ±	0.1V	1.5 ±	0.1V	1.8 ± 0).15V	2.5 ±	0.2V	3.3 ±	0.3V	UNIT
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
		^	В	–40°C to 85°C	0.5	55	0.5	37	0.5	27	0.5	15	0.5	11	0.5	10	0.5	8	0.5	9	
	Propagation	A	D	–40°C to 125°C	0.5	55	0.5	37	0.5	27	0.5	15	0.5	11	0.5	10	0.5	8	0.5	9	nc
t _{pd}	delay	B A	^	–40°C to 85°C	0.5	41	0.5	29	0.5	24	0.5	15	0.5	10	0.5	9	0.5	7	0.5	6	ns
				–40°C to 125°C	0.5	41	0.5	29	0.5	24	0.5	15	0.5	10	0.5	9	0.5	7	0.5	6	
				–40°C to 85°C	0.5	30	0.5	30	0.5	30	0.5	30	0.5	30	0.5	30	0.5	30	0.5	30	
	Disable time	ŌE A	A	–40°C to 125°C	0.5	30	0.5	30	0.5	30	0.5	30	0.5	30	0.5	30	0.5	30	0.5	30	na
t _{dis}		OE	в	–40°C to 85°C	0.5	132	0.5	99	0.5	79	0.5	31	0.5	24	0.5	21	0.5	18	0.5	18	ns
				–40°C to 125°C	0.5	132	0.5	99	0.5	79	0.5	31	0.5	24	0.5	21	0.5	18	0.5	18	
			A	–40°C to 85°C	0.5	45	0.5	45	0.5	45	0.5	45	0.5	45	0.5	45	0.5	45	0.5	45	
	Enable time	Enable time	A	–40°C to 125°C	0.5	45	0.5	45	0.5	45	0.5	45	0.5	45	0.5	45	0.5	45	0.5	45	na
t _{en}	Enable time		в	–40°C to 85°C	0.5	164	0.5	108	0.5	79	0.5	58	0.5	41	0.5	35	0.5	27	0.5	24	ns
		D	–40°C to 125°C	0.5	164	0.5	108	0.5	79	0.5	58	0.5	41	0.5	35	0.5	27	0.5	24		

5.10 Switching Characteristics, V_{CCA} = 1.5V

										E	B-Port S	Supply	Voltage	(V _{ссв})							
P	ARAMETER	FROM	то	Test Conditions	0.7 ± 0	0.05V	0.8 ± 0	.04V	0.9 ± 0	.045V	1.2 ±	0.1V	1.5 ±	0.1V	1.8 ± 0).15V	2.5 ±	0.2V	3.3 ±	0.3V	UNIT
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
		^	в	–40°C to 85°C	0.5	21	0.5	21	0.5	18	0.5	11	0.5	9	0.5	8	0.5	7	0.5	6	
+	Propagation	A		–40°C to 125°C	0.5	21	0.5	21	0.5	18	0.5	11	0.5	9	0.5	8	0.5	7	0.5	6	ns
^L pd	delay	R A	^	–40°C to 85°C	0.5	37	0.5	24	0.5	18	0.5	11	0.5	9	0.5	8	0.5	5	0.5	5	115
		B		–40°C to 125°C	0.5	37	0.5	24	0.5	18	0.5	11	0.5	9	0.5	8	0.5	5	0.5	5	
			A	–40°C to 85°C	0.5	21	0.5	21	0.5	21	0.5	21	0.5	21	0.5	21	0.5	21	0.5	21	
+	Disable time			–40°C to 125°C	0.5	21	0.5	21	0.5	21	0.5	21	0.5	21	0.5	21	0.5	21	0.5	21	ns
t _{dis}	s Disable time OE	OF	в	–40°C to 85°C	0.5	131	0.5	97	0.5	77	0.5	29	0.5	21	0.5	19	0.5	15	0.5	15	115
		OE B		–40°C to 125°C	0.5	131	0.5	97	0.5	77	0.5	29	0.5	21	0.5	19	0.5	15	0.5	15	



5.10 Switching Characteristics, V_{CCA} = 1.5V (continued)

										E	B-Port S	Supply	Voltage	(V _{CCB})							
P	ARAMETER	FROM	то	Test Conditions	0.7 ± 0	.05V	0.8 ± 0	.04V	0.9 ± 0	.045V	1.2 ±	0.1V	1.5 ±	0.1V	1.8 ± 0).15V	2.5 ± (0.2V	3.3 ±	0.3V	UNIT
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
		OE	^	–40°C to 85°C	0.5	26	0.5	26	0.5	26	0.5	26	0.5	26	0.5	26	0.5	26	0.5	26	
+	Enable time	0L		–40°C to 125°C	0.5	26	0.5	26	0.5	26	0.5	26	0.5	26	0.5	26	0.5	26	0.5	26	ns
l'en		<u>n</u> e	B	–40°C to 85°C	0.5	109	0.5	84	0.5	68	0.5	47	0.5	35	0.5	29	0.5	22	0.5	20	
	OE E		–40°C to 125°C	0.5	109	0.5	84	0.5	68	0.5	47	0.5	35	0.5	29	0.5	22	0.5	20		

See Figure 1 and Table 1 for test circuit and loading. See Figure 2, Figure 3, and Figure 4 for measurement waveforms.

5.11 Switching Characteristics, V_{CCA} = 1.8V

										I	B-Port S	Supply	Voltage	(V _{CCB})							
P	ARAMETER	FROM	то	Test Conditions	0.7 ± 0).05V	0.8 ± 0	.04V	0.9 ± 0	.045V	1.2 ±	0.1V	1.5 ±	0.1V	1.8 ± ().15V	2.5 ±	0.2V	3.3 ±	0.3V	UNIT
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
		A	в	–40°C to 85°C	0.5	15	0.5	15	0.5	13	0.5	9	0.5	8	0.5	7	0.5	6	0.5	6	
+	Propagation	A		–40°C to 125°C	0.5	15	0.5	15	0.5	13	0.5	9	0.5	8	0.5	7	0.5	6	0.5	6	n 0
t _{pd}	delay	в	A –	–40°C to 85°C	0.5	40	0.5	23	0.5	17	0.5	10	0.5	8	0.5	7	0.5	5	0.5	4	ns
		D		–40°C to 125°C	0.5	40	0.5	23	0.5	17	0.5	10	0.5	8	0.5	7	0.5	5	0.5	4	
		OE	Α	–40°C to 85°C	0.5	18	0.5	18	0.5	18	0.5	18	0.5	18	0.5	18	0.5	18	0.5	18	
+	Disable time			–40°C to 125°C	0.5	18	0.5	18	0.5	18	0.5	18	0.5	18	0.5	18	0.5	18	0.5	18	
t _{dis}	Disable time	OE	В	–40°C to 85°C	0.5	130	0.5	96	0.5	76	0.5	28	0.5	21	0.5	18	0.5	15	0.5	14	ns
				–40°C to 125°C	0.5	130	0.5	96	0.5	76	0.5	28	0.5	21	0.5	18	0.5	15	0.5	14	
			A	–40°C to 85°C	0.5	20	0.5	20	0.5	20	0.5	20	0.5	20	0.5	20	0.5	20	0.5	20	
+	Enable time	Enable time		–40°C to 125°C	0.5	20	0.5	20	0.5	20	0.5	20	0.5	20	0.5	20	0.5	20	0.5	20	ns
t _{en}		в	–40°C to 85°C	0.5	102	0.5	75	0.5	62	0.5	41	0.5	32	0.5	27	0.5	20	0.5	18	115	
		OE		–40°C to 125°C	0.5	102	0.5	75	0.5	62	0.5	41	0.5	32	0.5	27	0.5	20	0.5	18	



5.12 Switching Characteristics, V_{CCA} = 2.5V

See Figure 1 and Table 1 for test circuit and loading	g. See Figure 2, Figure 3, and Figure 4 for measurement waveforms.
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										I	B-Port S	Supply	Voltage	(V _{CCB})							
P	ARAMETER	FROM	то	Test Conditions	0.7 ± 0	0.05V	0.8 ± 0	.04V	0.9 ± 0.	.045V	1.2 ±	0.1V	1.5 ±	0.1V	1.8 ± ().15V	2.5 ±	0.2V	3.3 ±	0.3V	UNIT
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
			В	–40°C to 85°C	0.5	11	0.5	11	0.5	10	0.5	7	0.5	5	0.5	5	0.5	5	0.5	5	
+	Propagation	A	D	–40°C to 125°C	0.5	11	0.5	11	0.5	11	0.5	7	0.5	5	0.5	5	0.5	5	0.5	5	ns
t _{pd}	delay	в	A	–40°C to 85°C	0.5	67	0.5	24	0.5	16	0.5	8	0.5	7	0.5	6	0.5	5	0.5	4	115
		B		–40°C to 125°C	0.5	67	0.5	24	0.5	16	0.5	8	0.5	7	0.5	6	0.5	5	0.5	4	
		OE	A	–40°C to 85°C	0.5	13	0.5	13	0.5	13	0.5	13	0.5	13	0.5	13	0.5	13	0.5	13	
+	Disable time			–40°C to 125°C	0.5	13	0.5	13	0.5	13	0.5	13	0.5	13	0.5	13	0.5	13	0.5	13	ns
t _{dis}		OE	В	–40°C to 85°C	0.5	128	0.5	95	0.5	76	0.5	27	0.5	20	0.5	17	0.5	13	0.5	13	115
				–40°C to 125°C	0.5	128	0.5	95	0.5	76	0.5	27	0.5	20	0.5	17	0.5	13	0.5	13	
			A	–40°C to 85°C	0.5	13	0.5	13	0.5	13	0.5	13	0.5	13	0.5	13	0.5	13	0.5	13	
	Enchlo timo	-	A	–40°C to 125°C	0.5	13	0.5	13	0.5	13	0.5	13	0.5	13	0.5	13	0.5	13	0.5	13	n 0
t _{en}	Enable time	B	–40°C to 85°C	0.5	120	0.5	70	0.5	56	0.5	36	0.5	26	0.5	22	0.5	18	0.5	16	ns	
		<u>OE</u> B		–40°C to 125°C	0.5	120	0.5	70	0.5	56	0.5	36	0.5	26	0.5	22	0.5	18	0.5	16	

5.13 Switching Characteristics, V_{CCA} = 3.3V

										I	B-Port S	Supply	Voltage	(V _{CCB})							
P	ARAMETER	FROM	то	Test Conditions	0.7 ± 0	0.05V	0.8 ± 0	.04V	0.9 ± 0	.045V	1.2 ±	0.1V	1.5 ±	0.1V	1.8 ± 0).15V	2.5 ±	0.2V	3.3 ±	0.3V	UNIT
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
		^	в	–40°C to 85°C	0.5	10	0.5	10	0.5	9	0.5	6	0.5	5	0.5	4	0.5	4	0.5	4	
+	Propagation	A		–40°C to 125°C	0.5	10	0.5	10	0.5	9	0.5	6	0.5	5	0.5	4	0.5	4	0.5	4	ns
t _{pd}	delay	в	Δ	–40°C to 85°C	0.5	185	0.5	34	0.5	19	0.5	9	0.5	6	0.5	6	0.5	5	0.5	4	115
		D	A	–40°C to 125°C	0.5	185	0.5	34	0.5	19	0.5	9	0.5	6	0.5	6	0.5	5	0.5	4	
		ŌE	Δ	–40°C to 85°C	0.5	12	0.5	12	0.5	12	0.5	12	0.5	12	0.5	12	0.5	12	0.5	12	
t	Disable time	UE	A	–40°C to 125°C	0.5	12	0.5	12	0.5	12	0.5	12	0.5	12	0.5	12	0.5	12	0.5	12	ns
t _{dis}	lis Disable time	OF	в	–40°C to 85°C	0.5	141	0.5	95	0.5	75	0.5	27	0.5	19	0.5	17	0.5	13	0.5	12	
	ŌE		–40°C to 125°C	0.5	141	0.5	95	0.5	75	0.5	27	0.5	19	0.5	17	0.5	13	0.5	12		



5.13 Switching Characteristics, V_{CCA} = 3.3V (continued)

										I	B-Port S	Supply	Voltage	(V _{CCB})							
F	ARAMETER	FROM	то	Test Conditions	0.7 ± 0	0.05V	0.8 ± 0	.04V	0.9 ± 0	.045V	1.2 ±	0.1V	1.5 ±	0.1V	1.8 ± 0	.15V	2.5 ± (0.2V	3.3 ±	0.3V	UNIT
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
		ŌE	^	–40°C to 85°C	0.5	11	0.5	11	0.5	11	0.5	11	0.5	11	0.5	11	0.5	11	0.5	11	
+	Enable time	0L		–40°C to 125°C	0.5	11	0.5	11	0.5	11	0.5	11	0.5	11	0.5	11	0.5	11	0.5	11	ns
l'en		ŌE	в	–40°C to 85°C	0.5	189	0.5	82	0.5	59	0.5	35	0.5	24	0.5	20	0.5	16	0.5	14	
		OL		–40°C to 125°C	0.5	189	0.5	82	0.5	59	0.5	35	0.5	24	0.5	20	0.5	16	0.5	14	



5.14 Operating Characteristics: T_A = 25°C

	PARAMETER	TEST CONDITIONS	V _{CCA}	V _{CCB}	MIN	TYP	MAX	UNIT
			0.7V	0.7V		2.2		_
			0.8V	0.8V		2.1		
			0.9V	0.9V		2.1		
	Power Dissipation Capacitance	CL = 0, RL = Open f =	1.2V	1.2V		2.1		
	per transceiver (A to B: outputs enabled)	1MHz, tr = tf = 1ns	1.5V	1.5V		2.0		pF
			1.8V	1.8V		2.0		
			2.5V	2.5V		2.1		
			3.3V	3.3V		2.3		
			0.7V	0.7V		1.5		
			0.8V	0.8V		1.5		
			0.9V	0.9V		1.5		
	Power Dissipation Capacitance per transceiver (A to B: outputs disabled)	CL = 0, RL = Open f = 1MHz, tr = tf = 1ns	1.2V	1.2V		1.4		pF
			1.5V	1.5V		1.4		
			1.8V	1.8V		1.4		
			2.5V	2.5V		1.4		
			3.3V	3.3V		1.6		
pdA		CL = 0, RL = Open f = 1MHz, tr = tf = 1ns	0.7V	0.7V		12.1		
			0.8V	0.8V		12.1		
			0.9V	0.9V		12.1		
	Power Dissipation Capacitance		1.2V	1.2V		12.4		
	per transceiver (B to A: outputs enabled)		1.5V	1.5V		13.0		pF
	,		1.8V	1.8V		14.2		
			2.5V	2.5V		17.4		
			3.3V	3.3V		20.1		
			0.7V	0.7V		1.1		
			0.8V	0.8V		1.1		
			0.9V	0.9V		1.1		
	Power Dissipation Capacitance	CL = 0, RL = Open f =	1.2V	1.2V		1.1		- 5
	per transceiver (B to A: outputs disabled)	1MHz, tr = tf = 1ns	1.5V	1.5V		1.1		pF
	,		1.8V	1.8V		1.1		
			2.5V	2.5V		1.1		
			3.3V	3.3V		1.1		



5.14 Operating Characteristics: T_A = 25°C (continued)

	PARAMETER	TEST CONDITIONS	V _{CCA}	V _{CCB}	MIN	TYP	MAX	UNIT	
			0.7V	0.7V		12.1			
			0.8V	0.8V		12.1		- pF	
			0.9V	0.9V		12.1			
	Power Dissipation Capacitance	CL = 0, RL = Open f =	1.2V	1.2V		12.4			
	per transceiver (A to B: outputs enabled)	1MHz, tr = tf = 1ns	1.5V	1.5V		12.9			
			1.8V	1.8V		14.1			
			2.5V	2.5V		17.2			
			3.3V	3.3V		20.1			
			0.7V	0.7V		1.1			
			0.8V	0.8V		1.1			
			0.9V	0.9V		1.1			
	Power Dissipation Capacitance per transceiver (A to B: outputs	CL = 0, RL = Open f = 1MHz, tr = tf = 1ns	1.2V	1.2V		1.1		ъĘ	
	disabled)		1.5V	1.5V		1.1		pF	
			1.8V	1.8V		1.1			
			2.5V	2.5V		1.1			
			3.3V	3.3V		1.1			
pdB		CL = 0, RL = Open f = 1MHz, tr = tf = 1ns	0.7V	0.7V		1.2			
			0.8V	0.8V		1.8			
			0.9V	0.9V		1.8			
	Power Dissipation Capacitance per transceiver (B to A: outputs		1.2V	1.2V		1.7		~ Г	
	enabled)		1.5V	1.5V		1.7		pF	
			1.8V	1.8V		1.7			
			2.5V	2.5V		2			
			3.3V	3.3V		2.5			
			0.7V	0.7V		1.1			
			0.8V	0.8V		1.8			
			0.9V	0.9V		1.8			
	Power Dissipation Capacitance	CL = 0, RL = Open f =	1.2V	1.2V		1.7			
	per transceiver (B to A: outputs disabled)	1MHz, tr = tf = 1ns	1.5V	1.5V		1.7		pF	
	, ,		1.8V	1.8V		1.7			
			2.5V	2.5V		2			
			3.3V	3.3V		2.1			

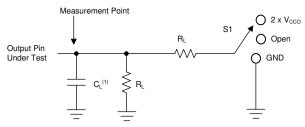


6 Parameter Measurement Information

6.1 Load Circuit and Voltage Waveforms

Unless otherwise noted, all input pulses are supplied by generators having the following characteristics:

- f = 1MHz
- Z_O = 50Ω
- dv/dt ≤ 1ns/V

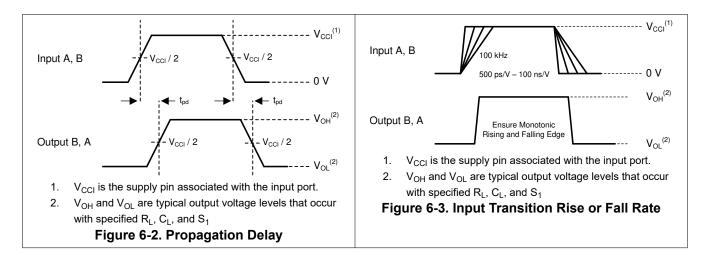


A. C_L includes probe and jig capacitance.

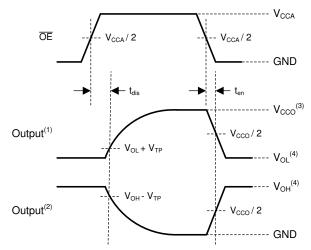
Figure 6-1. Load Circuit

Table 6-1. Load Circuit Conditions

Parameter	V _{cco}	RL	CL	S ₁	V _{TP}					
Input transition rise or fall rate	0.65V - 3.6V	1MΩ	15pF	Open	N/A					
Propagation (dolay) time	1.1V – 3.6V	2kΩ	15pF	Open	N/A					
Propagation (delay) time	0.65V - 0.95V	20kΩ	15pF	Open	N/A					
Enable time, disable time	3V – 3.6V	2kΩ	15pF	2 × V _{CCO}	0.3V					
	1.65V – 2.7V	2kΩ	15pF	2 × V _{CCO}	0.15V					
	1.1V – 1.6V	2kΩ	15pF	2 × V _{CCO}	0.1V					
	0.65V - 0.95V	20kΩ	15pF	2 × V _{CCO}	0.1V					
	3V – 3.6V	2kΩ	15pF	GND	0.3V					
Enclus times disclus times	1.65V – 2.7V	2kΩ	15pF	GND	0.15V					
Enable time, disable time	1.1V – 1.6V	2kΩ	15pF	GND	0.1V					
	0.65V – 0.95V	20kΩ	15pF	GND	0.1V					
		Parameter V_{CCO} Input transition rise or fall rate $0.65V - 3.6V$ Propagation (delay) time $1.1V - 3.6V$ $0.65V - 0.95V$ $3V - 3.6V$ Enable time, disable time $3V - 3.6V$ $1.65V - 2.7V$ $1.1V - 1.6V$ $0.65V - 0.95V$ $3V - 3.6V$ Enable time, disable time $3V - 3.6V$ $1.65V - 2.7V$ $1.1V - 1.6V$ $0.65V - 0.95V$ $3V - 3.6V$	$\begin{tabular}{ c c c c } \hline Parameter & V_{CCO} & R_L \\ \hline Input transition rise or fall rate & 0.65V - 3.6V & 1M\Omega \\ \hline Propagation (delay) time & 1.1V - 3.6V & 2k\Omega \\ \hline 0.65V - 0.95V & 20k\Omega \\ \hline 0.65V - 0.95V & 20k\Omega \\ \hline 1.65V - 2.7V & 2k\Omega \\ \hline 1.1V - 1.6V & 2k\Omega \\ \hline 0.65V - 0.95V & 20k\Omega \\ \hline 3V - 3.6V & 2k\Omega \\ \hline 0.65V - 0.95V & 20k\Omega \\ \hline 3V - 3.6V & 2k\Omega \\ \hline 1.65V - 2.7V & 2k\Omega \\ \hline 1.65V - 2.7V & 2k\Omega \\ \hline 1.65V - 2.7V & 2k\Omega \\ \hline 1.1V - 1.6V & 2k$	Parameter V_{CCO} R_L C_L Input transition rise or fall rate $0.65V - 3.6V$ $1M\Omega$ $15pF$ Propagation (delay) time $1.1V - 3.6V$ $2k\Omega$ $15pF$ $0.65V - 0.95V$ $20k\Omega$ $15pF$ $0.65V - 0.95V$ $20k\Omega$ $15pF$ $0.65V - 2.7V$ $2k\Omega$ $15pF$ $1.1V - 1.6V$ $2k\Omega$ $15pF$ $1.1V - 1.6V$ $2k\Omega$ $15pF$ $0.65V - 0.95V$ $20k\Omega$ $15pF$ $1.1V - 1.6V$ $2k\Omega$ $15pF$ $0.65V - 0.95V$ $20k\Omega$ $15pF$ $0.65V - 0.95V$ $20k\Omega$ $15pF$ $0.65V - 0.95V$ $20k\Omega$ $15pF$ $1.1V - 1.6V$ $2k\Omega$ $15pF$ $1.65V - 2.7V$ $2k\Omega$ $15pF$ $1.65V - 2.7V$ $2k\Omega$ $15pF$ $1.1V - 1.6V$ $2k\Omega$ $15pF$	Parameter V_{CCO} R_L C_L S_1 Input transition rise or fall rate $0.65V - 3.6V$ $1M\Omega$ $15pF$ OpenPropagation (delay) time $1.1V - 3.6V$ $2k\Omega$ $15pF$ Open $0.65V - 0.95V$ $20k\Omega$ $15pF$ Open $0.65V - 0.95V$ $20k\Omega$ $15pF$ Open $0.65V - 0.95V$ $20k\Omega$ $15pF$ $2 \times V_{CCO}$ $1.65V - 2.7V$ $2k\Omega$ $15pF$ $2 \times V_{CCO}$ $1.1V - 1.6V$ $2k\Omega$ $15pF$ $2 \times V_{CCO}$ $0.65V - 0.95V$ $20k\Omega$ $15pF$ GND Enable time, disable time $1.65V - 2.7V$ $2k\Omega$ $15pF$ GND $1.65V - 2.7V$ $2k\Omega$ $15pF$ GND					







- A. Output waveform on the condition that input is driven to a valid Logic Low.
- B. Output waveform on the condition that input is driven to a valid Logic High.
- C. V_{CCO} is the supply pin associated with the output port.
- D. V_{OH} and V_{OL} are typical output voltage levels with specified R_L, C_L, and S_1.

Figure 6-4. Enable Time And Disable Time

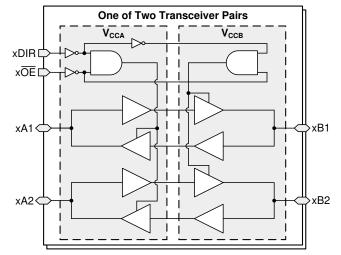


7 Detailed Description

7.1 Overview

The SN74AXC4T245 is a 4-bit, dual-supply noninverting bidirectional voltage level translation device. Ax pins and control pins (1DIR, 2DIR,1 \overline{OE} , and 2 \overline{OE}) are referenced to V_{CCA} logic levels, and Bx pins are referenced to V_{CCB} logic levels. The A port is able to accept I/O voltages ranging from 0.65V to 3.6V, while the B port can accept I/O voltages from 0.65V to 3.6V. A high on DIR allows data transmission from A to B and a low on DIR allows data transmission from B to A when \overline{OE} is set to low. When \overline{OE} is set to high, both Ax and Bx pins are in the high-impedance state. See *Device Functional Modes* for a summary of the operation of the control logic.

7.2 Functional Block Diagram



7.3 Feature Description

7.3.1 Standard CMOS Inputs

Standard CMOS inputs are high impedance and are typically modeled as a resistor in parallel with the input capacitance given in the *Electrical Characteristics*. The worst case resistance is calculated with the maximum input voltage, given in the *Absolute Maximum Ratings*, and the maximum input leakage current, given in the *Electrical Characteristics*, using ohm's law ($R = V \div I$).

Signals applied to the inputs need to have fast edge rates, as defined by $\Delta t/\Delta v$ in *Recommended Operating Conditions* to avoid excessive current consumption and oscillations. If a slow or noisy input signal is required, a device with a Schmitt-trigger input should be used to condition the input signal prior to the standard CMOS input.

7.3.2 Balanced High-Drive CMOS Push-Pull Outputs

A balanced output allows the device to sink and source similar currents. The high drive capability of this device creates fast edges into light loads so routing and load conditions should be considered to prevent ringing. Additionally, the outputs of this device are capable of driving larger currents than the device can sustain without being damaged. The electrical and thermal limits defined in the *Absolute Maximum Ratings* must be followed at all times.

7.3.3 Partial Power Down (I_{off})

The inputs and outputs for this device enter a high-impedance state when the device is powered down, inhibiting current backflow into the device. The maximum leakage into or out of any input or output pin on the device is specified by I_{off} in the *Electrical Characteristics*.

7.3.4 V_{CC} Isolation

The inputs and outputs for this device enter a high-impedance state when either supply is <100mV.



7.3.5 Over-voltage Tolerant Inputs

Input signals to this device can be driven above the supply voltage so long as they remain below the maximum input voltage value specified in the *Recommended Operating Conditions*.

7.3.6 Glitch-free Power Supply Sequencing

Either supply rail may be powered on or off in any order without producing a glitch on the I/Os (that is, where the output erroneously transitions to VCC when it should be held low). Glitches of this nature can be misinterpreted by a peripheral as a valid data bit, which could trigger a false device reset of the peripheral, a false device configuration of the peripheral, or even a false data initialization by the peripheral. For more information regarding the power up glitch performance of the AXC family of level translators, see the *Glitch Free Power Sequencing With AXC Level Translators* application report

7.3.7 Negative Clamping Diodes

The inputs and outputs to this device have negative clamping diodes as depicted in Figure 7-1.

CAUTION

Voltages beyond the values specified in the *Absolute Maximum Ratings* table can cause damage to the device. The input negative-voltage and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

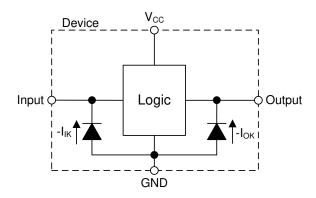


Figure 7-1. Electrical Placement of Clamping Diodes for Each Input and Output

7.3.8 Fully Configurable Dual-Rail Design

Both the V_{CCA} and V_{CCB} pins can be supplied at any voltage from 0.65V to 3.6V, making the device suitable for translating between any of the voltage nodes (0.7V, 0.8V, 0.9V, 1.2V, 1.8V, 2.5V and 3.3V).

7.3.9 I/Os with Integrated Static Pull-Down Resistors

To avoid floating inputs on the I/Os, this device has $71k\Omega$ typical integrated weak pull-downs on all data I/Os. This feature allows all inputs to be left floating without the concern for unstable outputs or increased current consumption. This also reduces external component count for applications where not all channels are used or need to be fixed low. If an external pull-up is required, then it should be no larger than $7k\Omega$ to avoid contention with the $71k\Omega$ internal pull-down.

7.3.10 Supports High-Speed Translation

The SN74AXC4T245 device can support high data-rate applications. The translated signal data rate can be up to 380Mbps when the signal is translated from 1.8V to 3.3V.



7.4 Device Functional Modes

Table 7-1. Function Table (Each 2-Bit Section)

CONTROL	INPUTS ⁽¹⁾	PORT S	OPERATION							
ŌĒ	DIR	A PORT	B PORT	OFERATION						
L	L	Output (Enabled)	Input (Hi-Z)	B data to A bus						
L	Н	Input (Hi-Z)	Output (Enabled)	A data to B bus						
н	х	Input (Hi-Z)	Input (Hi-Z)	Isolation						

(1) Input circuits of the data I/Os are always active.



8 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

8.1 Application Information

The SN74AXC4T245 device can be used in level-translation applications for interfacing devices or systems operating at different interface voltages with one another. The SN74AXC4T245 device is ideal for use in applications where a push-pull driver is connected to the data I/Os. The max data rate can be up to 380Mbps when device translates a signal from 1.8V to 3.3V.

One example application is shown in Figure 8-1, where the SN74AXC4T245 device is used to translate a low voltage UART signal from an SoC to a higher voltage signal which properly drive the inputs of the bluetooth module, and vice versa.



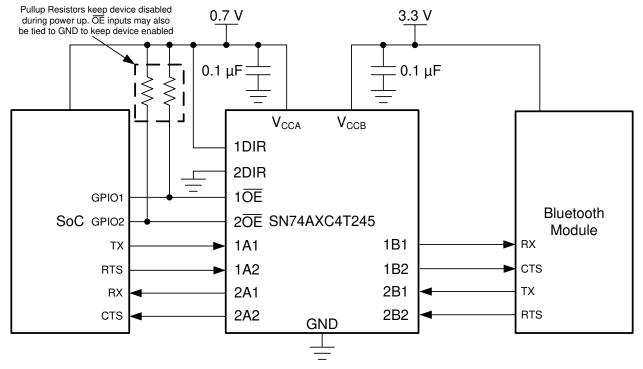


Figure 8-1. UART Interface Application

8.2.1 Design Requirements

For this design example, use the parameters listed in Table 8-1.

Table 8-1. Design Parameters

DESIGN PARAMETERS	EXAMPLE VALUES							
Input voltage range	0.65V to 3.6V							
Output voltage range	0.65V to 3.6V							

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8.2.2 Detailed Design Procedure

To begin the design process, determine the following:

- Input voltage range
 - Use the supply voltage of the device that is driving the SN74AXC4T245 device to determine the input voltage range. For a valid logic-high, the value must exceed the high-level input voltage (V_{IH}) of the input port. For a valid logic low the value must be less than the low-level input voltage (V_{IL}) of the input port.
- Output voltage range
 - Use the supply voltage of the device that the SN74AXC4T245 device is driving to determine the output voltage range.

8.2.3 Application Curve

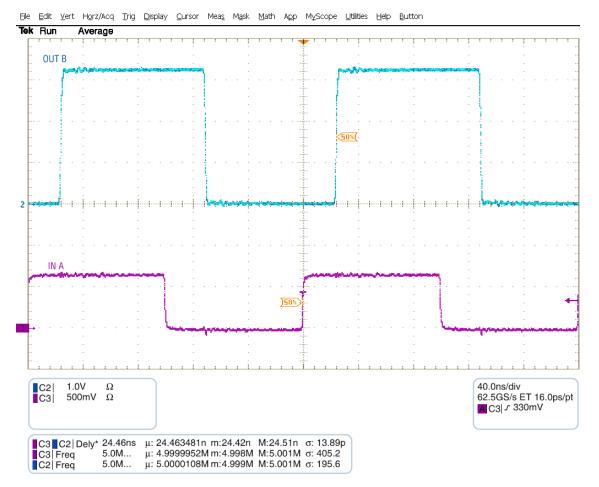


Figure 8-2. Up Translation at 2.5MHz (0.7V to 3.3V)

8.3 Power Supply Recommendations

Always apply a ground reference to the GND pins first. This device is designed for glitch free power sequencing without any supply sequencing requirements such as ramp order or ramp rate.

This device was designed with various power supply sequencing methods in mind to help prevent unintended triggering of downstream devices. For more information regarding the power up glitch performance of the AXC family of level translators, see the *Glitch Free Power Sequencing With AXC Level Translators* application report



8.4 Layout

8.4.1 Layout Guidelines

For device reliability, it is recommended to follow common printed-circuit board layout guidelines such as follows:

- Use bypass capacitors on the power supply pins and place them as close to the device as possible.
- Use short trace lengths to avoid excessive loading.

8.4.2 Layout Example

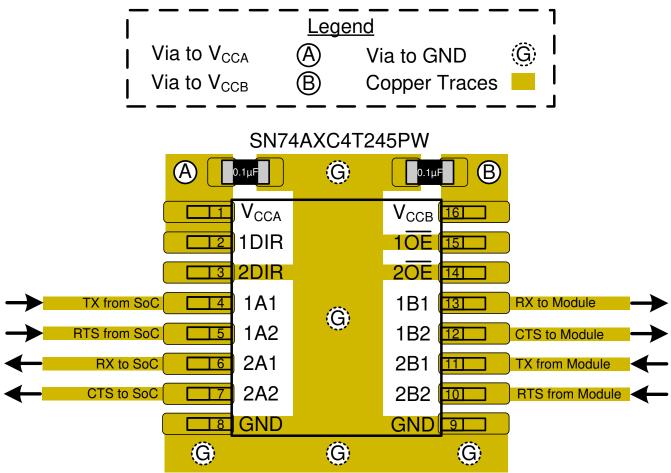


Figure 8-3. Layout Example



9 Device and Documentation Support

9.1 Documentation Support

9.1.1 Related Documentation

For related documentation, see the following:

- Texas Instruments, Implications of Slow or Floating CMOS Inputs application report
- Texas Instruments, Power Sequencing for AXC Family of Devices application report

9.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

9.3 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

9.4 Trademarks

TI E2E[™] is a trademark of Texas Instruments.

All trademarks are the property of their respective owners.

9.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

9.6 Glossary

TI Glossary This glossary lists and explains terms, acronyms, and definitions.

10 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

С	hanges from Revision A (July 2020) to Revision B (April 2024)	Page
•	Added the I/Os with Integrated Static Pull-Down Resistors section	19

С	hanges from Revision * (December 2018) to Revision A (July 2020)	Page
•	Updated the numbering format for tables, figures and cross-references throughout the document	1
•	Added BQB (WQFN) package option to Device Information table	1



11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.



PACKAGING INFORMATION

Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS	Lead finish/	MSL rating/	Op temp (°C)	Part marking
	(1)	(2)			(3)	Ball material	Peak reflow		(6)
						(4)	(5)		
SN74AXC4T245BQBR	Active	Production	WQFN (BQB) 16	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	4T245
SN74AXC4T245BQBR.A	Active	Production	WQFN (BQB) 16	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	4T245
SN74AXC4T245BQBRG4	Active	Production	WQFN (BQB) 16	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	4T245
SN74AXC4T245BQBRG4.A	Active	Production	WQFN (BQB) 16	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	4T245
SN74AXC4T245PWR	Active	Production	TSSOP (PW) 16	2000 LARGE T&R	Yes	NIPDAU SN	Level-1-260C-UNLIM	-40 to 125	SN4T245
SN74AXC4T245PWR.A	Active	Production	TSSOP (PW) 16	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	SN4T245
SN74AXC4T245PWR.B	Active	Production	TSSOP (PW) 16	2000 LARGE T&R	-	NIPDAU	Level-1-260C-UNLIM	-40 to 125	SN4T245
SN74AXC4T245PWRG4	Active	Production	TSSOP (PW) 16	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	SN4T245
SN74AXC4T245PWRG4.A	Active	Production	TSSOP (PW) 16	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	SN4T245
SN74AXC4T245RSVR	Active	Production	UQFN (RSV) 16	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	1TIR
SN74AXC4T245RSVR.A	Active	Production	UQFN (RSV) 16	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	1TIR
SN74AXC4T245RSVRG4.A	Active	Production	UQFN (RSV) 16	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	1TIR

⁽¹⁾ **Status:** For more details on status, see our product life cycle.

⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.



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24-Jul-2025

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OTHER QUALIFIED VERSIONS OF SN74AXC4T245 :

• Automotive : SN74AXC4T245-Q1

NOTE: Qualified Version Definitions:

• Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects



Texas

*All dimensions are nominal

STRUMENTS

TAPE AND REEL INFORMATION





QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74AXC4T245BQBR	WQFN	BQB	16	3000	180.0	12.4	2.8	3.8	1.2	4.0	12.0	Q1
SN74AXC4T245BQBRG4	WQFN	BQB	16	3000	180.0	12.4	2.8	3.8	1.2	4.0	12.0	Q1
SN74AXC4T245PWRG4	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
SN74AXC4T245RSVR	UQFN	RSV	16	3000	178.0	13.5	2.1	2.9	0.75	4.0	12.0	Q1



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PACKAGE MATERIALS INFORMATION

24-Jul-2025



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74AXC4T245BQBR	WQFN	BQB	16	3000	210.0	185.0	35.0
SN74AXC4T245BQBRG4	WQFN	BQB	16	3000	210.0	185.0	35.0
SN74AXC4T245PWRG4	TSSOP	PW	16	2000	353.0	353.0	32.0
SN74AXC4T245RSVR	UQFN	RSV	16	3000	189.0	185.0	36.0

RSV 16

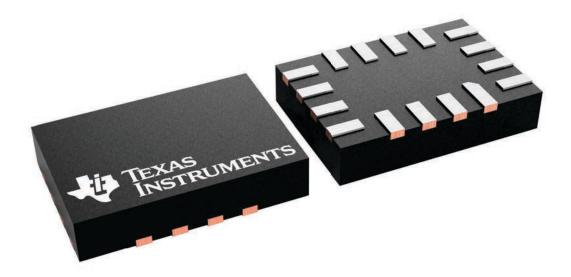
1.8 x 2.6, 0.4 mm pitch

GENERIC PACKAGE VIEW

UQFN - 0.55 mm max height

ULTRA THIN QUAD FLATPACK - NO LEAD

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.





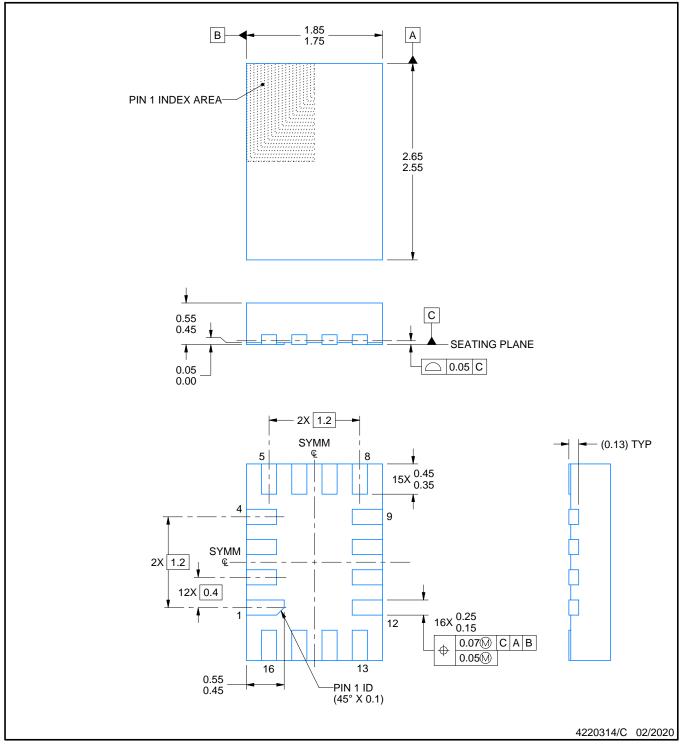
RSV0016A



PACKAGE OUTLINE

UQFN - 0.55 mm max height

ULTRA THIN QUAD FLATPACK - NO LEAD



NOTES:

All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
 This drawing is subject to change without notice.

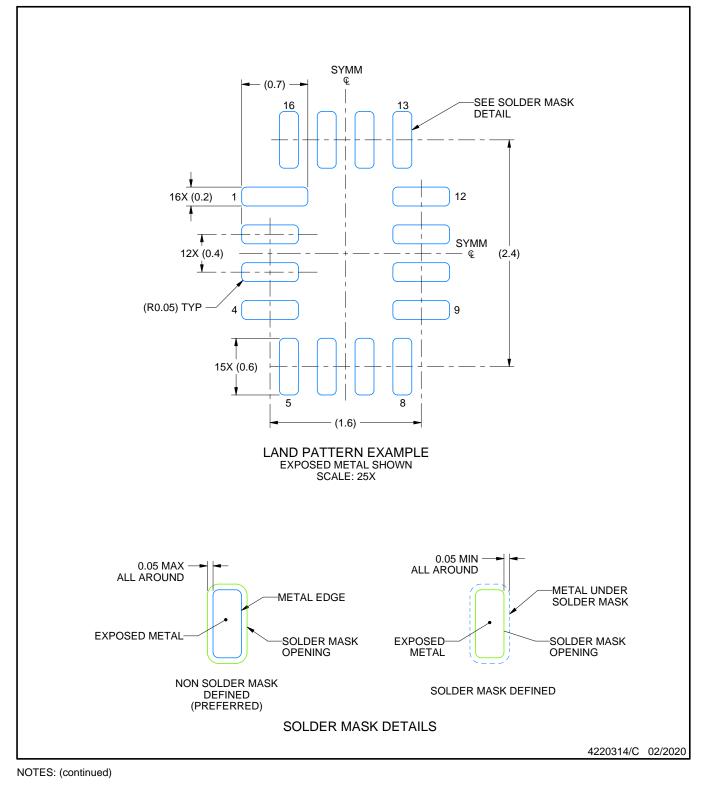


RSV0016A

EXAMPLE BOARD LAYOUT

UQFN - 0.55 mm max height

ULTRA THIN QUAD FLATPACK - NO LEAD



3. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).

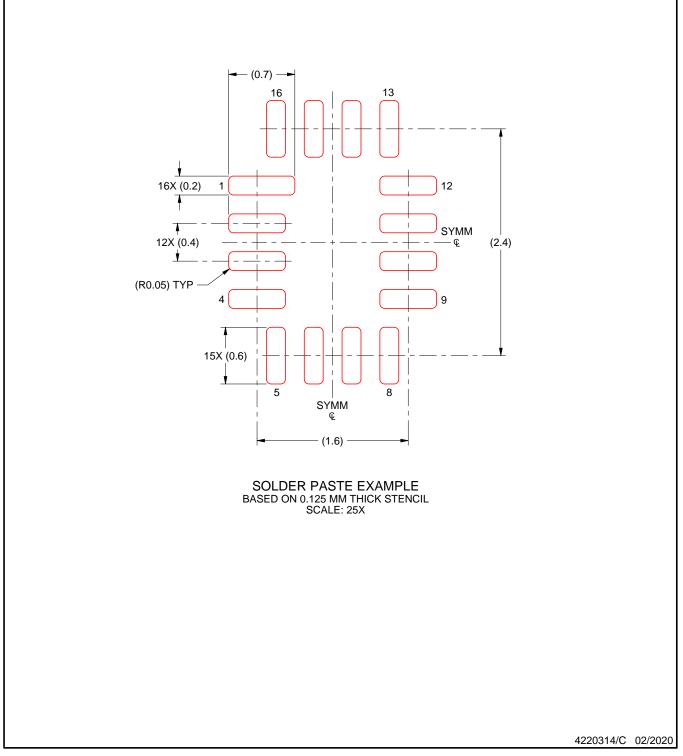


RSV0016A

EXAMPLE STENCIL DESIGN

UQFN - 0.55 mm max height

ULTRA THIN QUAD FLATPACK - NO LEAD



NOTES: (continued)

4. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



BQB 16

GENERIC PACKAGE VIEW

WQFN - 0.8 mm max height

PLASTIC QUAD FLATPACK - NO LEAD

2.5 x 3.5, 0.5 mm pitch

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.





BQB0016A

PACKAGE OUTLINE

WQFN - 0.8 mm max height

PLASTIC QUAD FLAT PACK-NO LEAD



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for optimal thermal and mechanical performance.



BQB0016A

EXAMPLE BOARD LAYOUT

WQFN - 0.8 mm max height

PLASTIC QUAD FLAT PACK-NO LEAD



NOTES: (continued)

- 4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- 5. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.

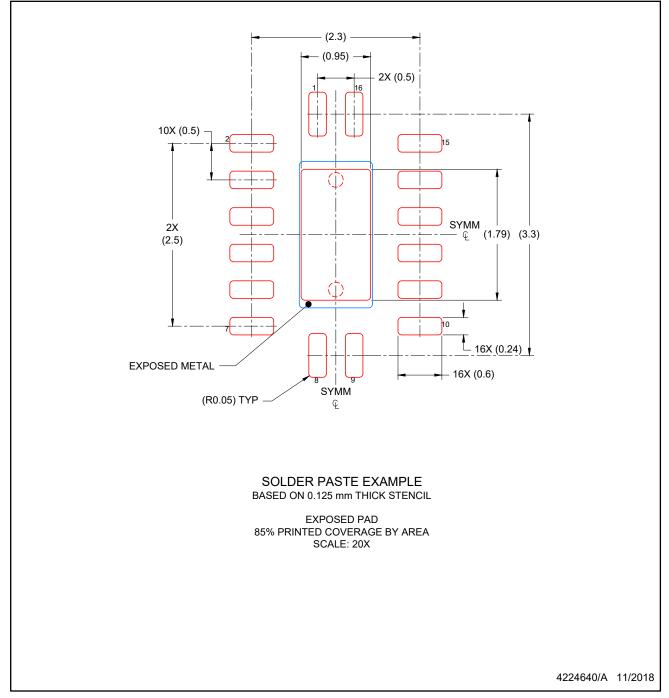


BQB0016A

EXAMPLE STENCIL DESIGN

WQFN - 0.8 mm max height

PLASTIC QUAD FLAT PACK-NO LEAD



NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



PW0016A



PACKAGE OUTLINE

TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M. 2. This drawing is subject to change without notice. 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.

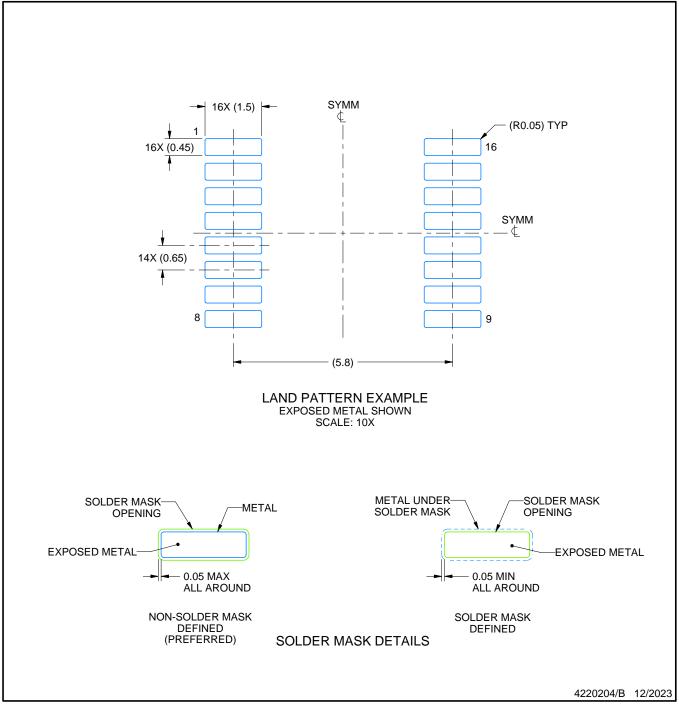


PW0016A

EXAMPLE BOARD LAYOUT

TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

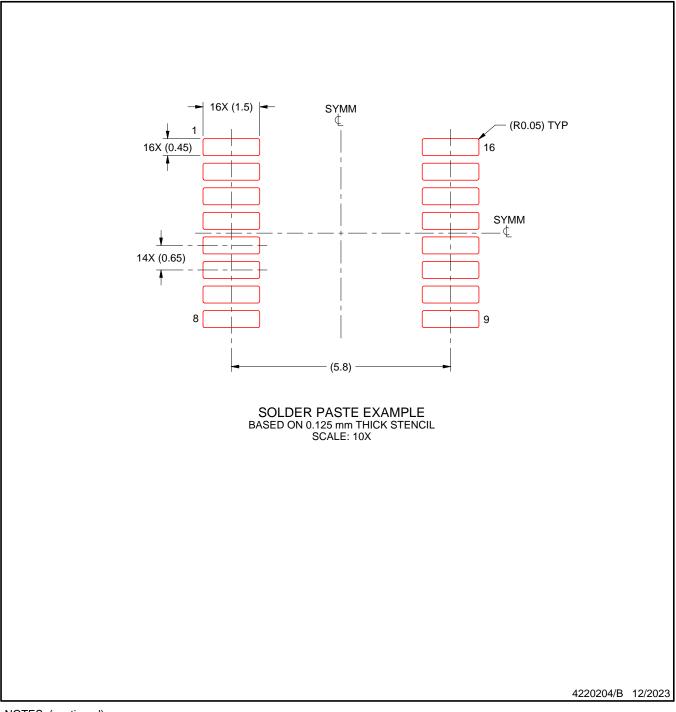


PW0016A

EXAMPLE STENCIL DESIGN

TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE



NOTES: (continued)

9. Board assembly site may have different recommendations for stencil design.



^{8.} Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

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